

AUTOMOTIVE GRADE

AUIRF3205Z AUIRF3205ZS

Features

- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching

Description

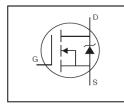
Repetitive Avalanche Allowed up to Timax

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive

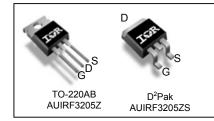
avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide

- Lead-Free, RoHS Compliant
- Automotive Qualified *

variety of other applications.



HEXFE	I Power MOSFEI
V _{DSS}	55V
R _{DS(on)} max.	$6.5 \mathrm{m}\Omega$
I _D (Silicon Limited)	110A
D (Package Limited)	75A



G	D	S
Gate	Drain	Source

Dage nort number	Dookogo Typo	Standard Pack	,	Orderable Part Number
Base part number	Package Type	Form	Quantity	Orderable Part Number
AUIRF3205Z	TO-220	Tube	50	AUIRF3205Z
ALUDE220570	D ² -Pak	Tube	50	AUIRF3205ZS
AUIRF3205ZS	р -Рак	Tape and Reel Left	800	AUIRF3205ZSTRL

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	110		
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	78	1	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Package Limited)	75	- A	
I _{DM}	Pulsed Drain Current ①	440		
P _D @T _C = 25°C	Maximum Power Dissipation	170	W	
-	Linear Derating Factor	1.1	W/°C	
V_{GS}	Gate-to-Source Voltage	± 20	V	
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②	180	I	
E _{AS} (tested)	Single Pulse Avalanche Energy Tested Value ®	250	- mJ	
I _{AR}	Avalanche Current ①	See Fig.15,16, 12a, 12b	Α	
E _{AR}	Repetitive Avalanche Energy ®		mJ	
TJ	Operating Junction and	-55 to + 175		
T_{STG}	Storage Temperature Range		°C	
·	Soldering Temperature, for 10 seconds (1.6mm from case)	300	7	
	Mounting torque, 6-32 or M3 screw⑦	10 lbf•in (1.1N•m)		

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case®		0.90	
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface ⑦	0.50		°C // //
$R_{\theta JA}$	Junction-to-Ambient ⑦		62	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount, steady state) ®		40	

HEXFET® is a registered trademark of Infineon.

^{*}Qualification standards can be found at www.infineon.com



Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_{D} = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.051		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		4.9	6.5	mΩ	$V_{GS} = 10V, I_D = 66A$ ③
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
gfs	Forward Trans conductance	71			S	$V_{DS} = 25V, I_{D} = 66A$
ı	Drain-to-Source Leakage Current			20		$V_{DS} = 55V, V_{GS} = 0V$
IDSS	Drain-to-Source Leakage Current			250	μΑ	$V_{DS} = 55V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I_{GSS}	Gate-to-Source Forward Leakage			200	n ^	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage			-200	nA	V _{GS} = -20V

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Q_g	Total Gate Charge	 76	110		I _D = 66A
Q_{gs}	Gate-to-Source Charge	 21		nC	$V_{DS} = 44V$
Q_{gd}	Gate-to-Drain Charge	 30			V _{GS} = 10V3
$t_{d(on)}$	Turn-On Delay Time	 18			$V_{DD} = 28V$
t _r	Rise Time	 95		20	$I_D = 66A$
$t_{d(off)}$	Turn-Off Delay Time	 45		ns	$R_G = 6.8\Omega$,
t _f	Fall Time	 67			V _{GS} = 10V ③
L _D	Internal Drain Inductance	 4.5		nH	Between lead, 6mm (0.25in.)
L _S	Internal Source Inductance	 7.5			from package and center of die contact:
C _{iss}	Input Capacitance	 3450			$V_{GS} = 0V$
C_{oss}	Output Capacitance	 550			$V_{DS} = 25V$
C_{rss}	Reverse Transfer Capacitance	 310		~F	f = 1.0MHz
Coss	Output Capacitance	 1940		pF	$V_{GS} = 0V, V_{DS} = 1.0V f = 1.0MHz$
Coss	Output Capacitance	 430			$V_{GS} = 0V, V_{DS} = 44V f = 1.0MHz$
Coss eff.	Effective Output Capacitance	 640			V_{GS} = 0V, V_{DS} = 0V to 44V \oplus

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current (Body Diode)			75		MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ①			440		integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 66A, V_{GS} = 0V$ 3
t _{rr}	Reverse Recovery Time		28	42	ns	$T_J = 25^{\circ}C$, $I_F = 66A$, $V_{DD} = 25V$
Q_{rr}	Reverse Recovery Charge		25	38	nC	di/dt = 100A/µs ③
t _{on}	Forward Turn-On Time	Intrins	Intrinsic turn-on time is negligible (turn-on is dominated by L_S+L_D)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig.11)
- \odot Limited by T_{Jmax} , starting T_J = 25°C, L = 0.08mH, R_G = 25 Ω , I_{AS} = 66A, V_{GS} =10V. Part not recommended for use above this value.
- \oplus C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- $\$ Limited by T_{Jmax} , see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- © This value determined from sample failure population, starting $T_J = 25$ °C, L = 0.08mH, $R_G = 25\Omega$, $I_{AS} = 66A$, $V_{GS} = 10V$.
- This is only applied to TO-220AB package.
- This is applied to D² Pak, When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994



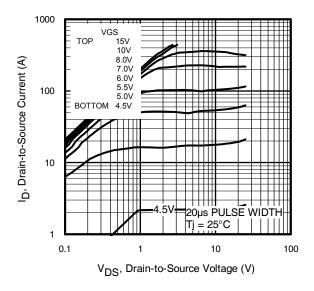


Fig. 1 Typical Output Characteristics

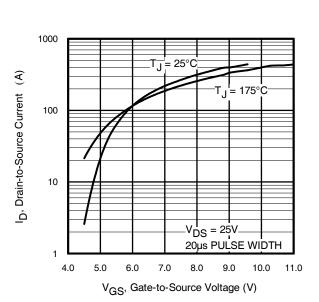


Fig. 3 Typical Transfer Characteristics

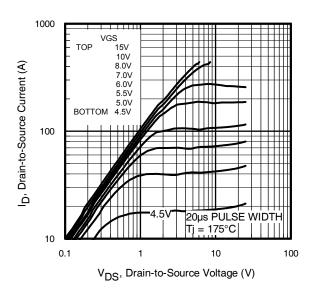


Fig. 2 Typical Output Characteristics

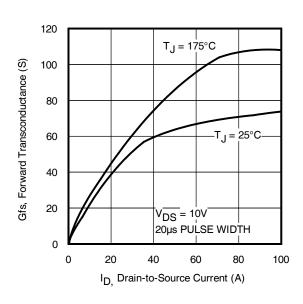


Fig. 4 Typical Forward Trans conductance vs. Drain Current



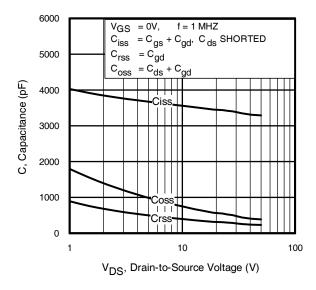


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

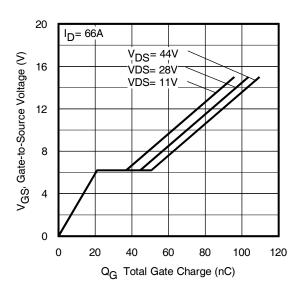


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

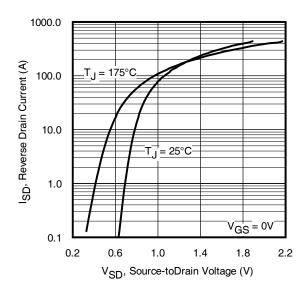


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

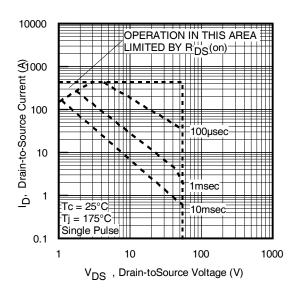


Fig 8. Maximum Safe Operating Area



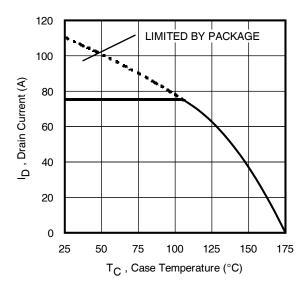


Fig 9. Maximum Drain Current vs. Case Temperature

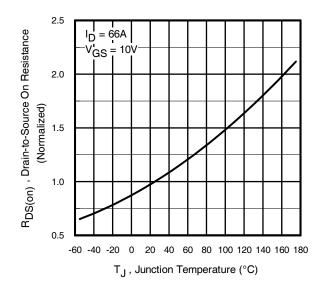


Fig 10. Normalized On-Resistance vs. Temperature

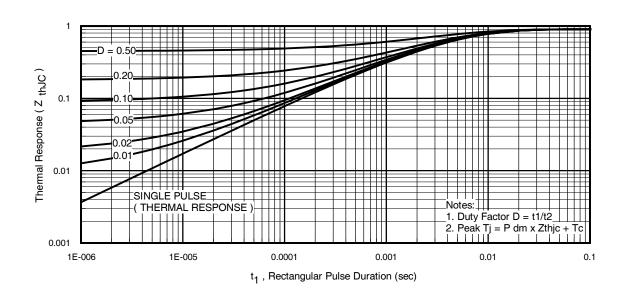


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



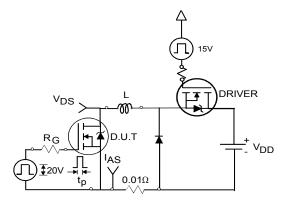


Fig 12a. Unclamped Inductive Test Circuit

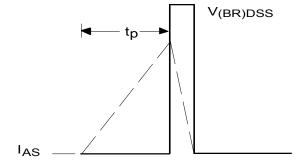


Fig 12b. Unclamped Inductive Waveforms

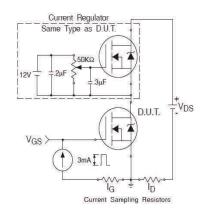


Fig 13a. Gate Charge Test Circuit

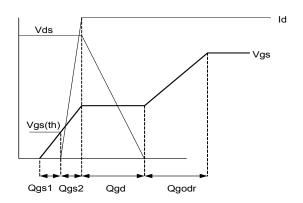


Fig 13b. Gate Charge Waveform

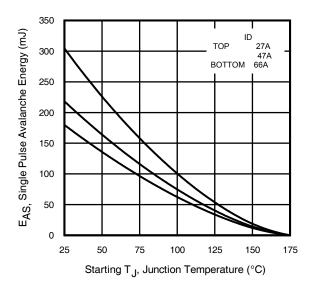


Fig 12c. Maximum Avalanche Energy vs. Drain Current

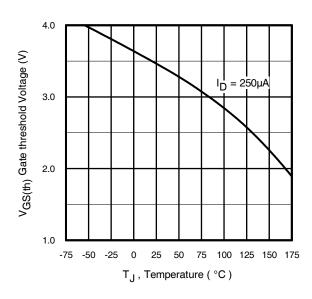


Fig 14. Threshold Voltage vs. Temperature



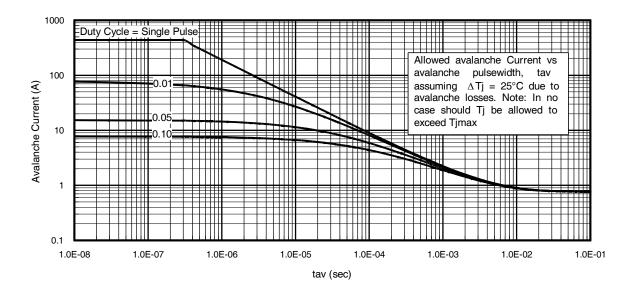
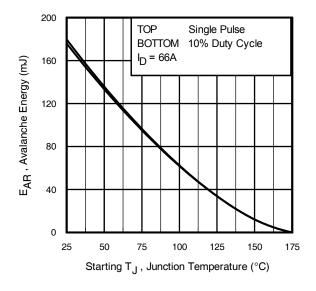


Fig 15. Avalanche Current vs. Pulse width



Notes on Repetitive Avalanche Curves, Figures 15, 16: (For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption:
 Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax}. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as Tjmax is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. lav = Allowable avalanche current.
- ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 14, 15).

tav = Average time in avalanche.

D = Duty cycle in avalanche = $t_{av} \cdot f$

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \text{ (ave)}} &= 1/2 \text{ (} 1.3 \cdot \text{BV} \cdot \text{I}_{av} \text{)} = \Delta \text{T} / \text{Z}_{\text{thJC}} \\ \\ I_{av} &= 2\Delta \text{T} / \text{ [} 1.3 \cdot \text{BV} \cdot \text{Z}_{\text{th}} \text{]} \\ \\ E_{AS \text{ (AR)}} &= P_{D \text{ (ave)}} \cdot t_{av} \end{split}$$

Fig 16. Maximum Avalanche Energy vs. Temperature



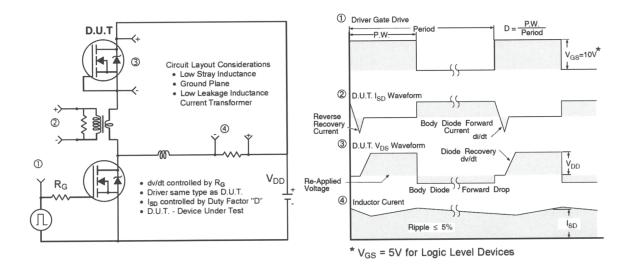


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

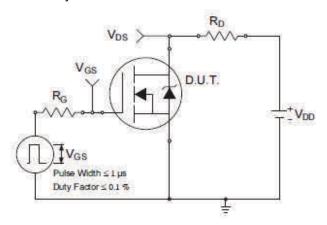


Fig 18a. Switching Time Test Circuit

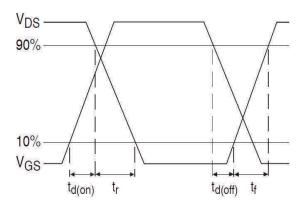
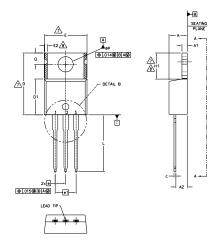
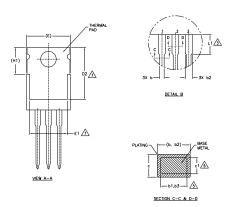


Fig 18b. Switching Time Waveforms



TO-220AB Package Outline (Dimensions are shown in millimeters (inches))





NOTES:

- DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994.
- DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].
- LEAD DIMENSION AND FINISH UNCONTROLLED IN L1
- DIMENSION D, D1 & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY.
- CONTROLLING DIMENSION: INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
- DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.
- OUTLINE CONFORMS TO JEDEC TO-220, EXCEPT A2 (max.) AND D2 (min.) WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE.

SYMBOL	MILLIMETERS		INC	HES		
	MIN.	MAX.	MIN.	MAX.	NOTES	
Α	3.56	4.83	.140	.190		
A1	1,14	1.40	.045	.055		
A2	2.03	2.92	.080	.115		
b	0.38	1.01	.015	.040		
ь1	0.38	0.97	.015	.038	5	
b2	1,14	1.78	.045	.070		
b3	1,14	1.73	.045	.068	5	
С	0.36	0.61	.014	.024		
c1	0.36	0.56	.014	.022	5	
D	14.22	16.51	.560	.650	4	
D1	8.38	9.02	.330	.355		
D2	11.68	12.88	.460	.507	7	
E	9.65	10.67	.380	.420	4,7	
E1	6.86	8.89	.270	.350	7	
E2	-	0.76	_	.030	8	
е	2.54 BSC		2.54 BSC .100 BSC		BSC	
e1	5.08	BSC	.200	BSC		
H1	5.84	6.86	.230	.270	7,8	
L	12.70	14.73	.500	.580		
L1	3.56	4.06	.140	.160	3	
øΡ	3.54	4.08	.139	.161		
Q	2.54	3.42	.100	.135		

LEAD ASSIGNMENTS

HEXFET

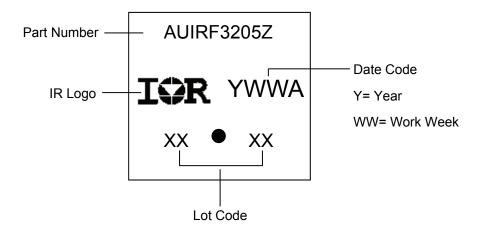
- 1.- GATE 2.- DRAIN 3.- SOURCE

1.- GATE 2.- COLLECTOR 3.- EMITTER

DIODES

- 1.- ANODE
- 2.- CATHODE 3.- ANODE

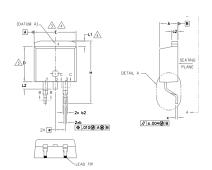
TO-220AB Part Marking Information

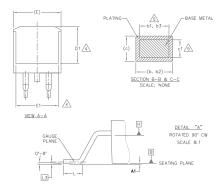


Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



D²Pak (TO-263AB) Package Outline (Dimensions are shown in millimeters (inches))





М		т	г		
ΙŊ	v	1	L	J	

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61, 63 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S	DIMENSIONS				
M B	MILLIMETERS		INC	HES	NOTES
O L	MIN.	MAX.	MIN.	MAX.	S
А	4.06	4.83	.160	.190	
A1	0.00	0.254	.000	.010	
Ь	0.51	0.99	.020	.039	
ь1	0.51	0.89	.020	.035	5
b2	1.14	1.78	.045	.070	
ь3	1.14	1.73	.045	.068	5
С	0.38	0.74	.015	.029	
с1	0.38	0.58	.015	.023	5
c2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	_	.270	_	4
E	9.65	10.67	.380	.420	3,4
E1	6.22	_	.245	_	4
е	2.54 BSC		.100	BSC	
Н	14.61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
L1	_	1.68	_	.066	4
L2	_	1.78	_	.070	
L3	0.25	BSC	.010	BSC	

LEAD ASSIGNMENTS

DIODES

1.— ANODE (TWO DIE) / OPEN (ONE DIE) 2, 4.— CATHODE 3.— ANODE

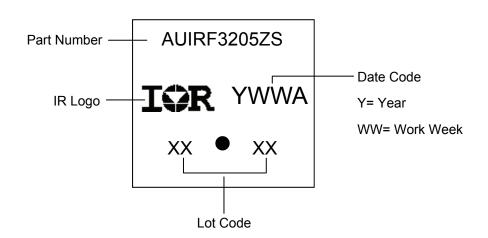
HEXFET

IGBTs, CoPACK

1.- GATE 2, 4.- DRAIN 3.- SOURCE

1.- GATE 2, 4.- COLLECTOR 3.- EMITTER

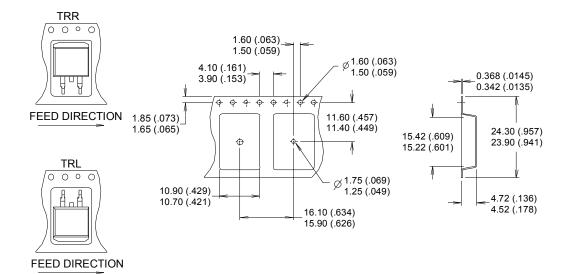
D²Pak (TO-263AB) Part Marking Information

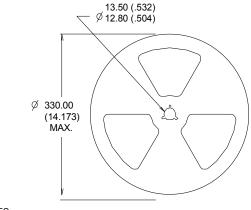


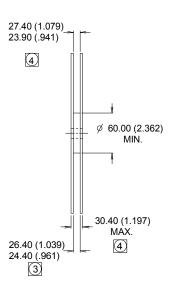
Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



D²Pak (TO-263AB) Tape & Reel Information (Dimensions are shown in millimeters (inches))







- NOTES:
- 1. COMFORMS TO EIA-418.
- 2. CONTROLLING DIMENSION: MILLIMETER.
- 3 DIMENSION MEASURED @ HUB.
- INCLUDES FLANGE DISTORTION @ OUTER EDGE.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification Information

Quaiiiiout	ion information						
	Qualification Level		Automotive				
			(per AEC-Q101)				
Qualificat			is part number(s) passed Automotive qualification. Infineon's				
		Industrial and C	Consumer qualification level is granted by extension of the higher				
		Automotive leve	el.				
Maiatura	Moisture Sensitivity Level		N/A				
Woisture			MSL1				
	NA salaire a NA salai	Class M4 (+/- 425V) [†]					
	Machine Model	AEC-Q101-002					
FOR	Liverage Dady Madal	Class H1C (+/- 2000V) [†]					
ESD	Human Body Model	AEC-Q101-001					
	Charried Davies Madel		Class C5 (+/- 1125V) [†]				
	Charged Device Model		AEC-Q101-005				
RoHS Compliant		Yes					
RoHS Co	RoHS Compliant		Yes				

[†] Highest passing voltage.

Revision History

Date	Comments
11/13/2015	Updated datasheet with corporate template
	Corrected ordering table on page 1.

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